

Annex B: Measurement Results
Tested Model :A7
Report Number: WSCT-ANAB-R&E251000083A-SAR

Measurement Report for Device, BACK, 2.4 GHz,Channel 6 (2437.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	2.4 GHz		2437.000, 6	7.07	1.81	41.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

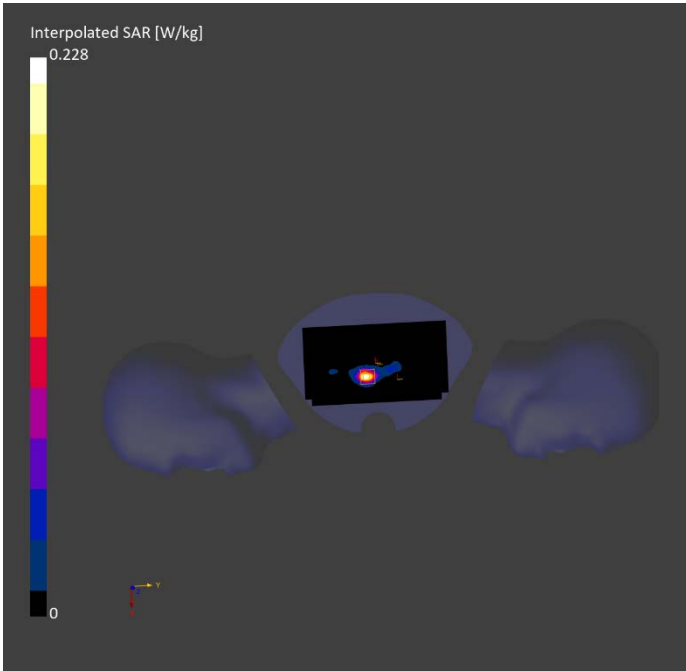
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-11-03	2025-11-03
psSAR1g [W/kg]	0.168	0.165
psSAR10g [W/kg]	0.069	0.063
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.4
Dist 3dB Peak [mm]		7.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 1 / 2A, Channel 48 (5240.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 1 / 2A		5240.000, 48	5.5	4.51	36.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

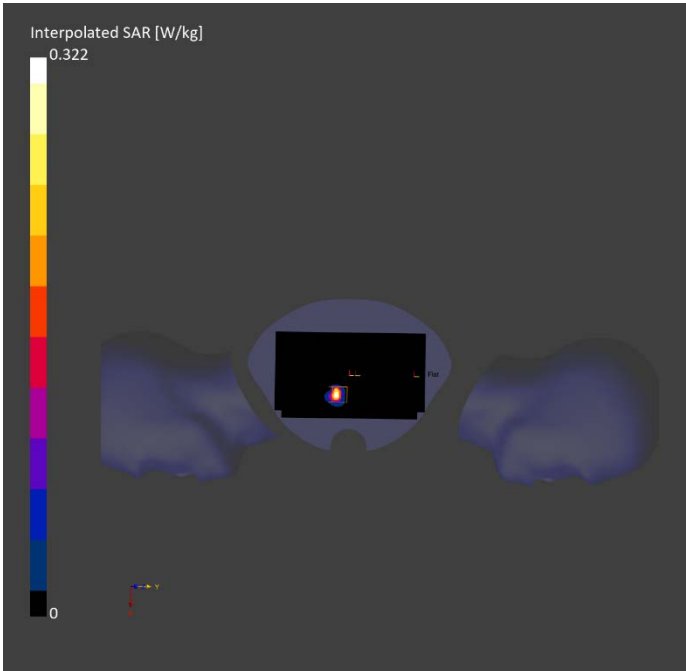
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-11-07	2025-11-07
psSAR1g [W/kg]	0.209	0.280
psSAR10g [W/kg]	0.057	0.066
Power Drift [dB]	0.02	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		67.0
Dist 3dB Peak [mm]		5.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 1 / 2A, Channel 58 (5290.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 1 / 2A		5290.000, 58	5.27	4.68	36.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

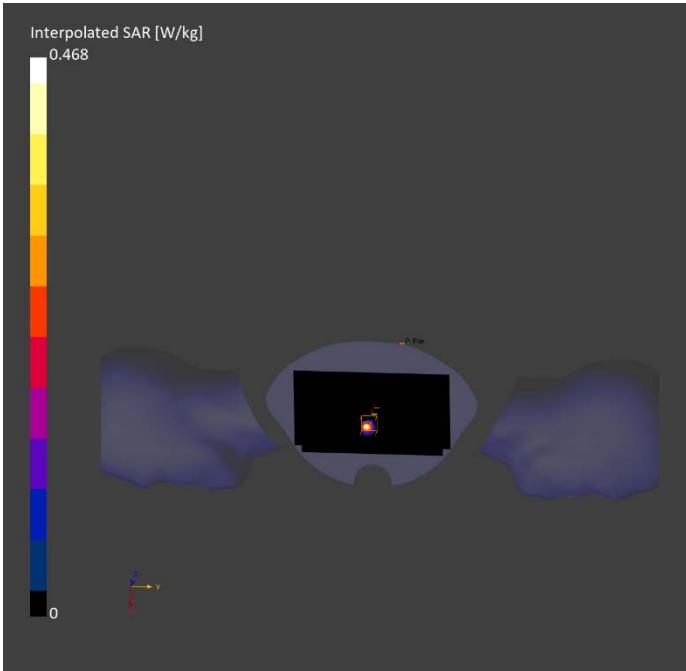
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-11-07	2025-11-07
psSAR1g [W/kg]	0.270	0.269
psSAR10g [W/kg]	0.058	0.050
Power Drift [dB]	0.13	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.4
Dist 3dB Peak [mm]		5.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 2C, Channel 100 (5550.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 2C		5550.000, 100	4.93	4.98	35.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

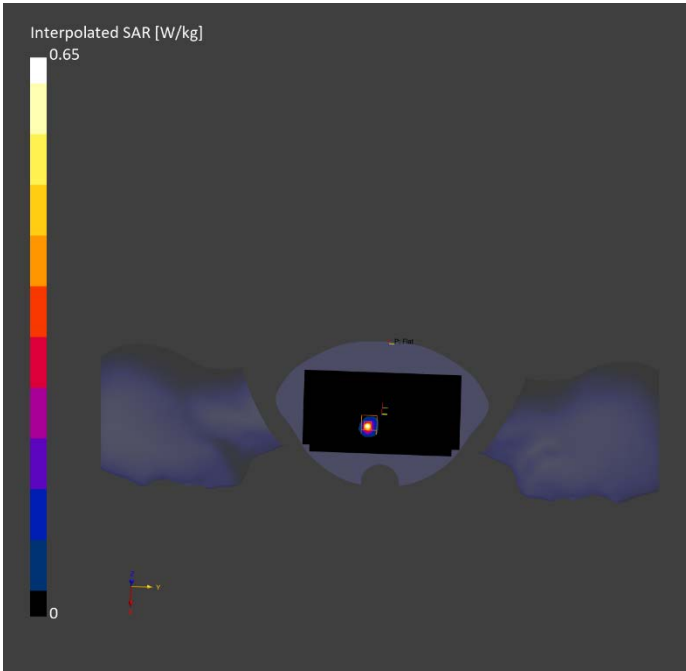
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-11-10	2025-11-10
psSAR1g [W/kg]	0.364	0.376
psSAR10g [W/kg]	0.092	0.091
Power Drift [dB]	0.22	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.3
Dist 3dB Peak [mm]		5.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 3, Channel 165 (5825.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 3		5825.000, 165	4.87	5.21	35.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

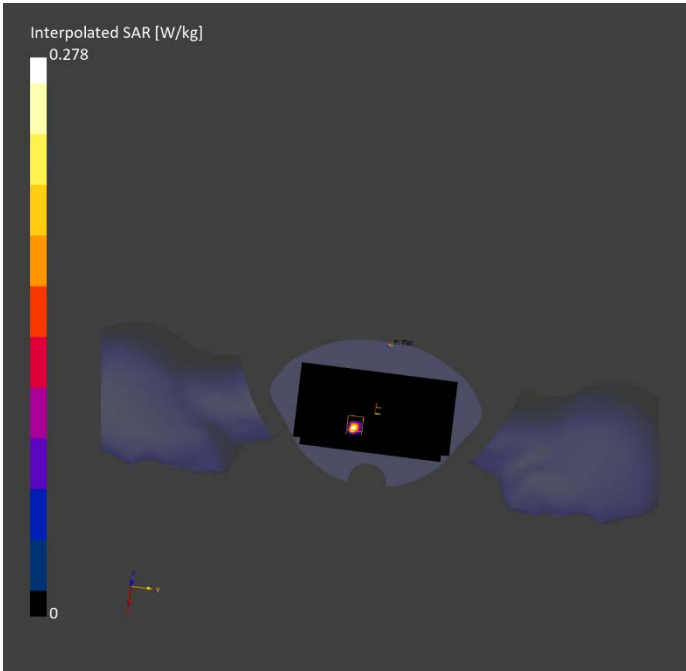
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-11-12	2025-11-12
psSAR1g [W/kg]	0.187	0.216
psSAR10g [W/kg]	0.041	0.038
Power Drift [dB]	0.10	-0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.0
Dist 3dB Peak [mm]		5.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, ISM 2.4 GHz Band,Channel 78 (2480.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	ISM 2.4 GHz Band		2480.000, 78	7.07	1.82	41.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-11-03	2025-11-03
psSAR1g [W/kg]	0.065	0.066
psSAR10g [W/kg]	0.026	0.023
Power Drift [dB]	-0.06	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.6
Dist 3dB Peak [mm]		7.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		

